TRANSMISSION ELECTRON MICROSCOPE (TEM)

Introduction: In 1931, Ernst Ruska and Max Knoll developed the first Transmission Electron Microscope but high-resolution TEM commercialized by RCA Lab in 1940. In 1986, Ruska was awarded the Nobel Prize in Physics for his work on the TEM.

- TEM is an electron microscope that uses a beam of electrons to create an image of a thin specimen, such as a tissue section or molecule.
- TEM is used to study the physical, chemical, and structural properties of materials at the nanoscale.

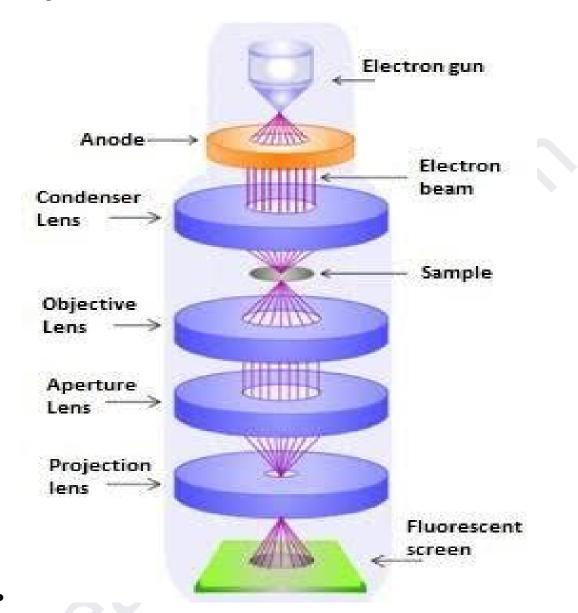
Principle:

• It works on the principle that a beam of high-energy (velocity) electrons accelerated under vacuum, focused by a condenser lens onto a specimen, and the emergent electron beam is focused by the objective lens. The final image forms on a fluorescent screen or camera for image viewing.

Main components of TEM

- 1. Electron gun
- 2. Anode
- 3. Condenser lens
- 4. Scanning coils
- 5. Specimen sample
- 6. Objective lens
- 7.Aperture
- 8. Projection lense
- 9. Fluorescent screen

Diagram / sketch:



Construction & Working:

- The virtual source at the top represents the Electron gun, which produces a high energy/velocity electron beam. These electrons are emitted from a small area of filament due to Cathode(-ve potential of the electrode).
- These emitted electrons are attracted and travel through anode, there by directionality (parallel electron beam).
- These **parallel beams** of high energy electrons accelerated under vacuum, focused by **condenser lens** (electromagnetic bending of electron beam) onto specimen/sample.
- The **objective lens** focuses the transmitted electrons from the sample into an **Aperture lens**.

- The aperture lens magnifies and focuses the image or diffraction pattern produced by the objective lens. And forms the magnified image on the object plane of the projector lens.
- The **projection lens** then projects the final image onto the viewing **Fluorescent screen** /camera.

Characteristics of Sample using TEM:

- 1. Sample used in Transmission Electron Microscope have several characteristics.
- 2.Thin & Vacuum stable
- 3.Free of contamination
- 4.Contrast-enhanced

Advantages:

- 1. High resolution imaging
- 2. High magnification
- 3. Versatile applications
- 4. Provides structural, morphological, and compositional information

Disadvantages:

- 1. Sample preparation and Vacuum requirement
- 2.Image is 2D projection
- 3. Expensive and requires specialized expertise